

C1812C823MATACTU

Aliases (C1812C823MATAC7800)

SMD Comm X8G HT150C, Ceramic, 0.082 uF, 20%, 250 VDC, X8G, SMD, MLCC, High Temperature, Ultra-Stable, 1812, 2.3 mm



| General Information | |
|--------------------------|--|
| Series | SMD Comm X8G HT150C |
| Style | SMD Chip |
| Description | SMD, MLCC, High Temperature, Ultra-Stable |
| Features | High Temperature, Ultra-Stable |
| RoHS | Yes |
| Termination | Tin |
| Marking | No |
| AEC-Q200 | No |
| Typical Component Weight | 87 mg |
| Shelf Life | 78 Weeks |
| MSL | 1 |

| Dimensions | |
|------------|-----------------|
| Chip Size | 1812 |
| L | 4.5mm +/-0.3mm |
| W | 3.2mm +/-0.3mm |
| Т | 2mm +/-0.20mm |
| S | 2.3mm MIN |
| В | 0.6mm +/-0.35mm |
| | |

| В | 0.6mm +/-0.35mm |
|--------------------------|--------------------------|
| | |
| Packaging Specifications | |
| Packaging | T&R, 180mm, Plastic Tape |
| Packaging Quantity | 500 |

| Specifications | |
|--|--|
| Capacitance | 0.082 uF |
| Measurement Condition | 1 kHz 1.0Vrms |
| Tolerance | 20% |
| Voltage DC | 250 VDC |
| Dielectric Withstanding Voltage | 625 VDC |
| Temperature Range | -55/+150°C |
| Temp. Coefficient | X8G |
| Capacitance Change with Reference to +25°C and 0 VDC Applied (TCC) | 30 ppm/C, 1kHz 1.0Vrms |
| Dissipation Factor | 0.1% 1 kHz 1.0Vrms |
| Aging Rate | 0% Loss/Decade Hour: Referee Time is 1000 Hours |
| Insulation Resistance | 12.1951 GOhms |

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